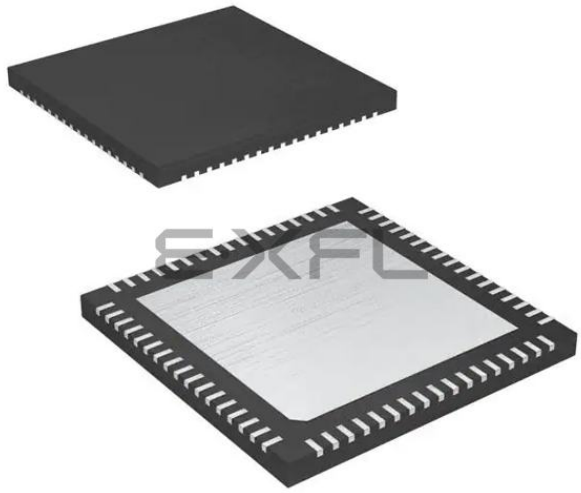

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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	ARM® Cortex®-M3
Core Size	32-Bit Single-Core
Speed	80MHz
Connectivity	CANbus, I²C, LINbus, SPI, UART/USART, USB
Peripherals	CapSense, DMA, LCD, POR, PWM, WDT
Number of I/O	38
Program Memory Size	256KB (256K x 8)
Program Memory Type	FLASH
EEPROM Size	2K x 8
RAM Size	64K x 8
Voltage - Supply (Vcc/Vdd)	1.71V ~ 5.5V
Data Converters	A/D 1x20b, 2x12b; D/A 4x8b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	68-VFQFN Exposed Pad
Supplier Device Package	68-QFN (8x8)
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/cy8c5888ltq-lp097

3. Pin Descriptions

IDAC0, IDAC1, IDAC2, IDAC3. Low-resistance output pin for high-current DACs (IDAC).

Opamp0out, Opamp1out, Opamp2out, Opamp3out. High current output of uncommitted opamp.[7]

Extref0, Extref1. External reference input to the analog system.

SAR0 EXTREF, SAR1 EXTREF. External references for SAR ADCs

Opamp0-, Opamp1-, Opamp2-, Opamp3-. Inverting input to uncommitted opamp.

Opamp0+, Opamp1+, Opamp2+, Opamp3+. Noninverting input to uncommitted opamp.

GPIO. Provides interfaces to the CPU, digital peripherals, analog peripherals, interrupts, LCD segment drive, and CapSense.[7]

I2C0: SCL, I2C1: SCL. I^2C SCL line providing wake from sleep on an address match. Any I/O pin can be used for I^2C SCL if wake from sleep is not required.

I2C0: SDA, I2C1: SDA. I^2C SDA line providing wake from sleep on an address match. Any I/O pin can be used for I^2C SDA if wake from sleep is not required.

Ind. Inductor connection to boost pump.

kHz XTAL: Xo, kHz XTAL: Xi. 32.768-kHz crystal oscillator pin.

MHz XTAL: Xo, MHz XTAL: Xi. 4 to 25-MHz crystal oscillator pin.

nTRST. Optional JTAG Test Reset programming and debug port connection to reset the JTAG connection.

SIO. Provides interfaces to the CPU, digital peripherals and interrupts with a programmable high threshold voltage, analog comparator, high sink current, and high impedance state when the device is unpowered.

SWDCK. SWD Clock programming and debug port connection.

SWDIO. SWD Input and Output programming and debug port connection.

TCK. JTAG Test Clock programming and debug port connection.

TDI. JTAG Test Data In programming and debug port connection.

TDO. JTAG Test Data Out programming and debug port connection.

TMS. JTAG Test Mode Select programming and debug port connection.

TRACECLK. Cortex-M3 TRACEPORT connection, clocks TRACEDATA pins.

TRACEDATA[3:0]. Cortex-M3 TRACEPORT connections, output data.

SWV. SWV output.

USBIO, D+. Provides D+ connection directly to a USB 2.0 bus. May be used as a digital I/O pin; it is powered from VDDD instead of from a VDDIO. Pins are Do Not Use (DNU) on devices without USB.

USBIO, D-. Provides D- connection directly to a USB 2.0 bus. May be used as a digital I/O pin; it is powered from VDDD instead of from a VDDIO. Pins are Do Not Use (DNU) on devices without USB.

VBOOST. Power sense connection to boost pump.

VBAT. Battery supply to boost pump.

VCCA. Output of the analog core regulator or the input to the analog core. Requires a 1uF capacitor to VSSA. The regulator output is not designed to drive external circuits. **Note that if you use the device with an external core regulator (externally regulated mode), the voltage applied to this pin must not exceed the allowable range of 1.71 V to 1.89 V.** When using the internal core regulator, (internally regulated mode, the default), do not tie any power to this pin. For details see Power System on page 26.

VCCD. Output of the digital core regulator or the input to the digital core. The two VCCD pins must be shorted together, with the trace between them as short as possible, and a 1uF capacitor to VSSD. The regulator output is not designed to drive external circuits. **Note that if you use the device with an external core regulator (externally regulated mode), the voltage applied to this pin must not exceed the allowable range of 1.71 V to 1.89 V.** When using the internal core regulator (internally regulated mode, the default), do not tie any power to this pin. For details see Power System on page 26.

VDDA. Supply for all analog peripherals and analog core regulator. **VDDA must be the highest voltage present on the device. All other supply pins must be less than or equal to VDDA.**

VDDD. Supply for all digital peripherals and digital core regulator. VDDD must be less than or equal to VDDA.

VSSA. Ground for all analog peripherals.

VSSB. Ground connection for boost pump.

VSSD. Ground for all digital logic and I/O pins.

VDDIO0, VDDIO1, VDDIO2, VDDIO3. Supply for I/O pins. Each VDDIO must be tied to a valid operating voltage (1.71 V to 5.5 V), and must be less than or equal to VDDA.

$\overline{\text{XRES}}$. External reset pin. Active low with internal pull-up.

Note
7. GPIOs with opamp outputs are not recommended for use with CapSense.

4.3.1 PHUB Features

- CPU and DMA controller are both bus masters to the PHUB
- Eight multi-layer AHB bus parallel access paths (spokes) for peripheral access
- Simultaneous CPU and DMA access to peripherals located on different spokes
- Simultaneous DMA source and destination burst transactions on different spokes
- Supports 8-, 16-, 24-, and 32-bit addressing and data

Table 4-3. PHUB Spokes and Peripherals

PHUB Spokes	Peripherals
0	SRAM
1	IOs, PICU, EMIF
2	PHUB local configuration, Power manager, Clocks, IC, SWV, EEPROM, Flash programming interface
3	Analog interface and trim, Decimator
4	USB, CAN, I2C, Timers, Counters, and PWMs
5	DFB
6	UDBs group 1
7	UDBs group 2

4.3.2 DMA Features

- 24 DMA channels
- Each channel has one or more transaction descriptors (TDs) to configure channel behavior. Up to 128 total TDs can be defined
- TDs can be dynamically updated
- Eight levels of priority per channel
- Any digitally routable signal, the CPU, or another DMA channel, can trigger a transaction
- Each channel can generate up to two interrupts per transfer
- Transactions can be stalled or canceled
- Supports transaction size of infinite or 1 to 64k bytes
- Large transactions may be broken into smaller bursts of 1 to 127 bytes
- TDs may be nested and/or chained for complex transactions

4.3.3 Priority Levels

The CPU always has higher priority than the DMA controller when their accesses require the same bus resources. Due to the system architecture, the CPU can never starve the DMA. DMA channels of higher priority (lower priority number) may interrupt current DMA transfers. In the case of an interrupt, the current transfer is allowed to complete its current transaction. To ensure latency limits when multiple DMA accesses are requested simultaneously, a fairness algorithm guarantees an interleaved minimum percentage of bus bandwidth for priority levels 2 through 7. Priority levels 0 and 1 do not take part in the fairness algorithm and may use 100% of the bus bandwidth. If a tie occurs on two DMA requests of the same priority level, a simple round robin method is used to evenly share the allocated bandwidth. The round robin allocation can be disabled for each DMA channel, allowing it to always be at the head of the line. Priority levels 2 to 7 are guaranteed the minimum bus bandwidth shown in Table 4-4 after the CPU and DMA priority levels 0 and 1 have satisfied their requirements.

Table 4-4. Priority Levels

Priority Level	% Bus Bandwidth
0	100.0
1	100.0
2	50.0
3	25.0
4	12.5
5	6.2
6	3.1
7	1.5

When the fairness algorithm is disabled, DMA access is granted based solely on the priority level; no bus bandwidth guarantees are made.

4.3.4 Transaction Modes Supported

The flexible configuration of each DMA channel and the ability to chain multiple channels allow the creation of both simple and complex use cases. General use cases include, but are not limited to:

4.3.4.1 Simple DMA

In a simple DMA case, a single TD transfers data between a source and sink (peripherals or memory location). The basic timing diagrams of DMA read and write cycles are shown in Figure 4-2. For more description on other transfer modes, refer to the Technical Reference Manual.

4.4 Interrupt Controller

The Cortex-M3 NVIC supports 16 system exceptions and 32 interrupts from peripherals, as shown in Table 4-5.

Table 4-5. Cortex-M3 Exceptions and Interrupts

Exception Number	Exception Type	Priority	Exception Table Address Offset	Function
			0x00	Starting value of R13 / MSP
1	Reset	-3 (highest)	0x04	Reset
2	NMI	-2	0x08	Non maskable interrupt
3	Hard fault	-1	0x0C	All classes of fault, when the corresponding fault handler cannot be activated because it is currently disabled or masked
4	MemManage	Programmable	0x10	Memory management fault, for example, instruction fetch from a nonexecutable region
5	Bus fault	Programmable	0x14	Error response received from the bus system; caused by an instruction prefetch abort or data access error
6	Usage fault	Programmable	0x18	Typically caused by invalid instructions or trying to switch to ARM mode
7–10	-	-	0x1C–0x28	Reserved
11	SVC	Programmable	0x2C	System service call via SVC instruction
12	Debug monitor	Programmable	0x30	Debug monitor
13	-	-	0x34	Reserved
14	PendSV	Programmable	0x38	Deferred request for system service
15	SYSTICK	Programmable	0x3C	System tick timer
16–47	IRQ	Programmable	0x40–0x3FC	Peripheral interrupt request #0 - #31

Bit 0 of each exception vector indicates whether the exception is executed using ARM or Thumb instructions. Because the Cortex-M3 only supports Thumb instructions, this bit must always be 1. The Cortex-M3 non maskable interrupt (NMI) input can be routed to any pin, via the DSI, or disconnected from all pins. See DSI Routing Interface Description on page 45.

The Nested Vectored Interrupt Controller (NVIC) handles interrupts from the peripherals, and passes the interrupt vectors to the CPU. It is closely integrated with the CPU for low latency interrupt handling. Features include:

- 32 interrupts. Multiple sources for each interrupt.
- Eight priority levels, with dynamic priority control.
- Priority grouping. This allows selection of preempting and non preempting interrupt levels.
- Support for tail-chaining, and late arrival, of interrupts. This enables back-to-back interrupt processing without the overhead of state saving and restoration between interrupts.
- Processor state automatically saved on interrupt entry, and restored on interrupt exit, with no instruction overhead.

If the same priority level is assigned to two or more interrupts, the interrupt with the lower vector number is executed first. Each interrupt vector may choose from three interrupt sources: Fixed Function, DMA, and UDB. The fixed function interrupts are direct connections to the most common interrupt sources and provide the lowest resource cost connection. The DMA interrupt sources provide direct connections to the two DMA interrupt sources provided per DMA channel. The third interrupt source for vectors is from the UDB digital routing array. This allows any digital signal available to the UDB array to be used as an interrupt source. All interrupt sources may be routed to any interrupt vector using the UDB interrupt source connections.

5.5 Nonvolatile Latches (NVLs)

PSoC has a 4-byte array of nonvolatile latches (NVLs) that are used to configure the device at reset. The NVL register map is shown in Table 5-3.

Table 5-2. Device Configuration NVL Register Map

Register Address	7	6	5	4	3	2	1	0
0x00	PRT3RDM[1:0]		PRT2RDM[1:0]		PRT1RDM[1:0]		PRT0RDM[1:0]	
0x01	PRT12RDM[1:0]		PRT6RDM[1:0]		PRT5RDM[1:0]		PRT4RDM[1:0]	
0x02	XRESMEN	DBGEN					PRT15RDM[1:0]	
0x03	DIG_PHS_DLY[3:0]				ECCEN	DPS[1:0]		CFGSPEED

The details for individual fields and their factory default settings are shown in Table 5-3:.

Table 5-3. Fields and Factory Default Settings

Field	Description	Settings
PRTxRDM[1:0]	Controls reset drive mode of the corresponding IO port. See "Reset Configuration" on page 39. All pins of the port are set to the same mode.	00b (default) - high impedance analog 01b - high impedance digital 10b - resistive pull up 11b - resistive pull down
XRESMEN	Controls whether pin P1[2] is used as a GPIO or as an external reset. P1[2] is generally used as a GPIO, and not as an external reset.	0 (default) - GPIO 1 - external reset
DBGEN	Debug Enable allows access to the debug system, for third-party programmers.	0 - access disabled 1 (default) - access enabled
CFGSPEED	Controls the speed of the IMO-based clock during the device boot process, for faster boot or low-power operation	0 (default) - 12 MHz IMO 1 - 48 MHz IMO
DPS[1:0]	Controls the usage of various P1 pins as a debug port. See "Programming, Debug Interfaces, Resources" on page 61.	00b - 5-wire JTAG 01b (default) - 4-wire JTAG 10b - SWD 11b - debug ports disabled
ECCEN	Controls whether ECC flash is used for ECC or for general configuration and data storage. See "Flash Program Memory" on page 19.	0 - ECC disabled 1 (default) - ECC enabled
DIG_PHS_DLY[3:0]	Selects the digital clock phase delay.	See the TRM for details.

Although PSoC Creator provides support for modifying the device configuration NVLs, the number of NVL erase/write cycles is limited – see "Nonvolatile Latches (NVL)" on page 117.

6.4.13 SIO as Comparator

This section applies only to SIO pins. The adjustable input level feature of the SIOs as explained in the Adjustable Input Level on page 38 can be used to construct a comparator. The threshold for the comparator is provided by the SIO's reference generator. The reference generator has the option to set the analog signal routed through the analog global line as threshold for the comparator. Note that a pair of SIO pins share the same threshold.

The digital input path in Figure 6-9 on page 35 illustrates this functionality. In the figure, 'Reference level' is the analog signal routed through the analog global. The hysteresis feature can also be enabled for the input buffer of the SIO, which increases noise immunity for the comparator.

6.4.14 Hot Swap

This section applies only to SIO pins. SIO pins support 'hot swap' capability to plug into an application without loading the signals that are connected to the SIO pins even when no power is applied to the PSoC device. This allows the unpowered PSoC to maintain a high impedance load to the external device while also preventing the PSoC from being powered through a SIO pin's protection diode.

Powering the device up or down while connected to an operational I2C bus may cause transient states on the SIO pins. The overall I2C bus design should take this into account.

6.4.15 Overvoltage Tolerance

All I/O pins provide an overvoltage tolerance feature at any operating VDD.

- There are no current limitations for the SIO pins as they present a high impedance load to the external circuit.
- The GPIO pins must be limited to 100 µA using a current limiting resistor. GPIO pins clamp the pin voltage to approximately one diode above the VDDIO supply.
- In case of a GPIO pin configured for analog input/output, the analog voltage on the pin must not exceed the VDDIO supply voltage to which the GPIO belongs.

A common application for this feature is connection to a bus such as I^2C where different devices are running from different supply voltages. In the I^2C case, the PSoC chip is configured into the Open Drain, Drives Low mode for the SIO pin. This allows an external pull-up to pull the I^2C bus voltage above the PSoC pin supply. For example, the PSoC chip could operate at 1.8 V, and an external device could run from 5 V. Note that the SIO pin's VIH and VIL levels are determined by the associated VDDIO supply pin.

The SIO pin must be in one of the following modes: 0 (high impedance analog), 1 (high impedance digital), or 4 (open drain drives low). See Figure 6-11 for details. Absolute maximum ratings for the device must be observed for all I/O pins.

6.4.16 Reset Configuration

While reset is active all I/Os are reset to and held in the High Impedance Analog state. After reset is released, the state can be reprogrammed on a port-by-port basis to pull-down or pull-up. To ensure correct reset operation, the port reset configuration data is stored in special nonvolatile registers. The stored reset data is automatically transferred to the port reset configuration registers at reset release.

6.4.17 Low Power Functionality

In all low power modes the I/O pins retain their state until the part is awakened and changed or reset. To awaken the part, use a pin interrupt, because the port interrupt logic continues to function in all low power modes.

6.4.18 Special Pin Functionality

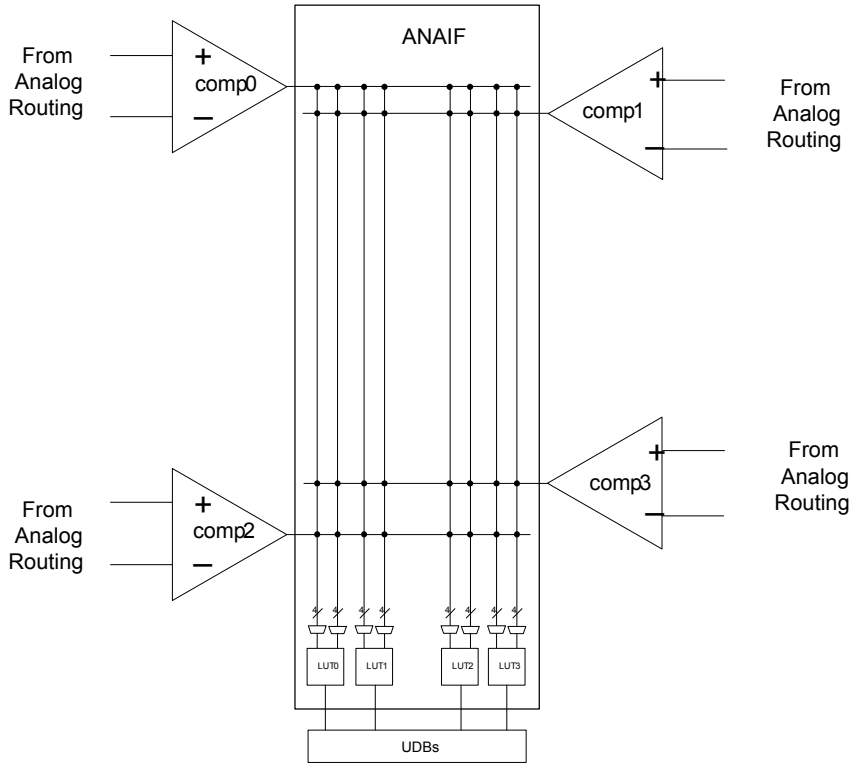
Some pins on the device include additional special functionality in addition to their GPIO or SIO functionality. The specific special function pins are listed in "Pinouts" on page 6. The special features are:

- Digital
  - 4- to 25-MHz crystal oscillator
  - 32.768-kHz crystal oscillator
  - Wake from sleep on I^2C address match. Any pin can be used for I^2C if wake from sleep is not required.
  - JTAG interface pins
  - SWD interface pins
  - SWV interface pins
  - TRACEPORT interface pins
  - External reset
- Analog
  - Opamp inputs and outputs
  - High current IDAC outputs
  - External reference inputs

6.4.19 JTAG Boundary Scan

The device supports standard JTAG boundary scan chains on all pins for board level test.

Figure 8-6. Analog Comparator



8.4.2 LUT

The CY8C58LP family of devices contains four LUTs. The LUT is a two input, one output lookup table that is driven by any one or two of the comparators in the chip. The output of any LUT is routed to the digital system interface of the UDB array. From the digital system interface of the UDB array, these signals can be connected to UDBs, DMA controller, I/O, or the interrupt controller.

The LUT control word written to a register sets the logic function on the output. The available LUT functions and the associated control word is shown in Table 8-2**.**

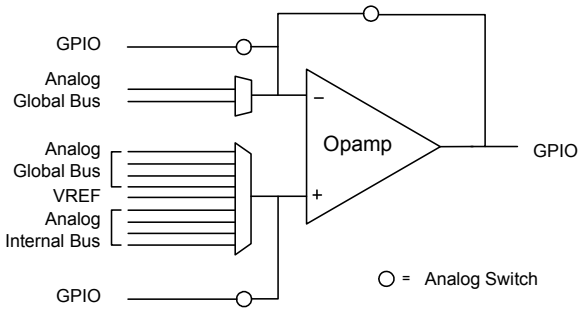
Table 8-2. LUT Function vs. Program Word and Inputs

Control Word	Output (A and B are LUT inputs)
0000b	**FALSE** (‘0’)
0001b	**A** AND **B**
0010b	**A** AND (NOT **B**)
0011b	A
0100b	(NOT **A**) AND **B**
0101b	B
0110b	**A** XOR **B**
0111b	**A** OR **B**
1000b	**A** NOR **B**
1001b	**A** XNOR **B**
1010b	NOT **B**
1011b	**A** OR (NOT **B**)
1100b	NOT **A**
1101b	(NOT **A**) OR **B**
1110b	**A** NAND **B**
1111b	**TRUE** (‘1’)

8.5 Opamps

The CY8C58LP family of devices contain four general purpose opamps.

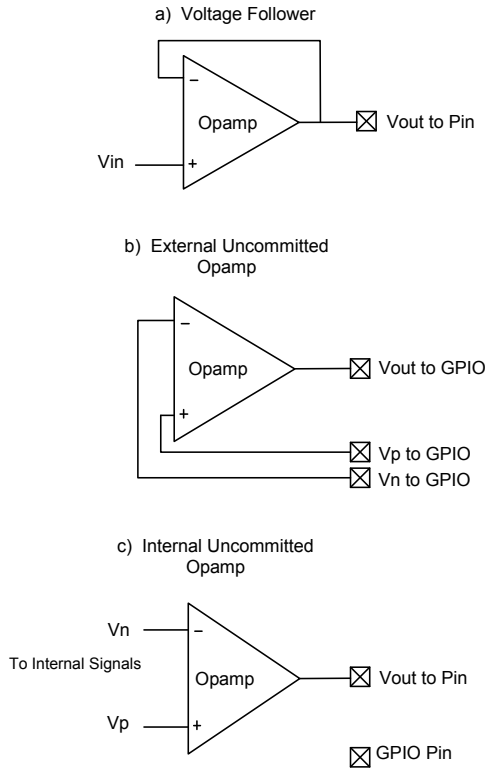
Figure 8-7. Opamp



The opamp is uncommitted and can be configured as a gain stage or voltage follower on external or internal signals.

See Figure 8-8. In any configuration, the input and output signals can all be connected to the internal global signals and monitored with an ADC, or comparator. The configurations are implemented with switches between the signals and GPIO pins.

Figure 8-8. Opamp Configurations



The opamp has three speed modes, slow, medium, and fast. The slow mode consumes the least amount of quiescent power and the fast mode consumes the most power. The inputs are able to swing rail-to-rail. The output swing is capable of rail-to-rail operation at low current output, within 50 mV of the rails. When driving high current loads (about 25 mA) the output voltage may only get within 500 mV of the rails.

8.6 Programmable SC/CT Blocks

The CY8C58LP family of devices contains four switched capacitor/continuous time (SC/CT) blocks. Each switched capacitor/continuous time block is built around a single rail-to-rail high bandwidth opamp.

Switched capacitor is a circuit design technique that uses capacitors plus switches instead of resistors to create analog functions. These circuits work by moving charge between capacitors by opening and closing different switches. Nonoverlapping in phase clock signals control the switches, so that not all switches are ON simultaneously.

The PSoC Creator tool offers a user friendly interface, which allows you to easily program the SC/CT blocks. Switch control and clock phase control configuration is done by PSoC Creator so users only need to determine the application use parameters such as gain, amplifier polarity, V_{REF} connection, and so on.

The same opamps and block interfaces are also connectable to an array of resistors which allows the construction of a variety of continuous time functions.

The opamp and resistor array is programmable to perform various analog functions including

- Naked Operational Amplifier - Continuous Mode
- Unity-Gain Buffer - Continuous Mode
- Programmable Gain Amplifier (PGA) - Continuous Mode
- Transimpedance Amplifier (TIA) - Continuous Mode
- Up/Down Mixer - Continuous Mode
- Sample and Hold Mixer (NRZ S/H) - Switched Cap Mode
- First Order Analog to Digital Modulator - Switched Cap Mode

8.6.1 Naked Opamp

The Naked Opamp presents both inputs and the output for connection to internal or external signals. The opamp has a unity gain bandwidth greater than 6.0 MHz and output drive current up to 650 µA. This is sufficient for buffering internal signals (such as DAC outputs) and driving external loads greater than 7.5 kohms.

8.6.2 Unity Gain

The Unity Gain buffer is a Naked Opamp with the output directly connected to the inverting input for a gain of 1.00. It has a -3 dB bandwidth greater than 6.0 MHz.

8.6.3 PGA

The PGA amplifies an external or internal signal. The PGA can be configured to operate in inverting mode or noninverting mode. The PGA function may be configured for both positive and negative gains as high as 50 and 49 respectively. The gain is adjusted by changing the values of R1 and R2 as illustrated in Figure 8-9. The schematic in Figure 8-9 shows the configuration and possible resistor settings for the PGA. The gain is switched from inverting and non inverting by changing the shared select value of the both the input muxes. The bandwidth for each gain case is listed in Table 8-3.

9.3 Debug Features

The CY8C58LP supports the following debug features:

- Halt and single-step the CPU
- View and change CPU and peripheral registers, and RAM addresses
- Six program address breakpoints and two literal access breakpoints
- Data watchpoint events to CPU
- Patch and remap instruction from flash to SRAM
- Debugging at the full speed of the CPU
- Compatible with PSoC Creator and MiniProg3 programmer and debugger
- Standard JTAG programming and debugging interfaces make CY8C58LP compatible with other popular third-party tools (for example, ARM / Keil)

9.4 Trace Features

The following trace features are supported:

- Instruction trace
- Data watchpoint on access to data address, address range, or data value
- Trace trigger on data watchpoint
- Debug exception trigger
- Code profiling
- Counters for measuring clock cycles, folded instructions, load/store operations, sleep cycles, cycles per instruction, interrupt overhead
- Interrupt events trace
- Software event monitoring, “printf-style” debugging

9.5 SWV and TRACEPORT Interfaces

The SWV and TRACEPORT interfaces provide trace data to a debug host via the Cypress MiniProg3 or an external trace port analyzer. The 5 pin TRACEPORT is used for rapid transmission of large trace streams. The single pin SWV mode is used to minimize the number of trace pins. SWV is shared with a JTAG pin. If debugging and tracing are done at the same time then SWD may be used with either SWV or TRACEPORT, or JTAG may be used with TRACEPORT, as shown in Table 9-1.

Table 9-1. Debug Configurations

Debug and Trace Configuration	GPIO Pins Used
All debug and trace disabled	0
JTAG	4 or 5
SWD	2
SWV	1
TRACEPORT	5
JTAG + TRACEPORT	9 or 10
SWD + SWV	3
SWD + TRACEPORT	7

9.6 Programming Features

The JTAG and SWD interfaces provide full programming support. The entire device can be erased, programmed, and verified. Designers can increase flash protection levels to protect firmware IP. Flash protection can only be reset after a full device erase. Individual flash blocks can be erased, programmed, and verified, if block security settings permit.

9.7 Device Security

PSoC 5LP offers an advanced security feature called device security, which permanently disables all test, programming, and debug ports, protecting your application from external access. The device security is activated by programming a 32-bit key (0x50536F43) to a Write Once Latch (WOL).

The WOL is a type of nonvolatile latch (NVL). The cell itself is an NVL with additional logic wrapped around it. Each WOL device contains four bytes (32 bits) of data. The wrapper outputs a ‘1’ if a super-majority (28 of 32) of its bits match a pre-determined pattern (0x50536F43); it outputs a ‘0’ if this majority is not reached. When the output is 1, the Write Once NV latch locks the part out of Debug and Test modes; it also permanently gates off the ability to erase or alter the contents of the latch. Matching all bits is intentionally not required, so that single (or few) bit failures do not deassert the WOL output. The state of the NVL bits after wafer processing is truly random with no tendency toward 1 or 0.

The WOL only locks the part after the correct 32-bit key (0x50536F43) is loaded into the NVL's volatile memory, programmed into the NVL's nonvolatile cells, and the part is reset. The output of the WOL is only sampled on reset and used to disable the access. This precaution prevents anyone from reading, erasing, or altering the contents of the internal memory.

The user can write the key into the WOL to lock out external access only if no flash protection is set (see “Flash Security” section on page 19). However, after setting the values in the WOL, a user still has access to the part until it is reset. Therefore, a user can write the key into the WOL, program the flash protection data, and then reset the part to lock it.

If the device is protected with a WOL setting, Cypress cannot perform failure analysis and, therefore, cannot accept RMAs from customers. The WOL can be read out via SWD port to electrically identify protected parts. The user can write the key in WOL to lock out external access only if no flash protection is set. For more information on how to take full advantage of the security features in PSoC see the PSoC 5 TRM.

Disclaimer

Note the following details of the flash code protection features on Cypress devices.

Cypress products meet the specifications contained in their particular Cypress datasheets. Cypress believes that its family of products is one of the most secure families of its kind on the market today, regardless of how they are used. There may be methods, unknown to Cypress, that can breach the code protection features. Any of these methods, to our knowledge, would be dishonest and possibly illegal. Neither Cypress nor any other semiconductor manufacturer can guarantee the security of their code. Code protection does not mean that we are guaranteeing the product as “unbreakable.”

Cypress is willing to work with the customer who is concerned about the integrity of their code. Code protection is constantly evolving. We at Cypress are committed to continuously improving the code protection features of our products.

Table 11-6. Inductive Boost Regulator DC Specifications (continued)

Parameter	Description	Conditions		Min	Typ	Max	Units
I_{OUT}	Output current	T_A = 0 °C–70 °C	V_{BAT} = 0.5 V–0.8 V	0	–	5	mA
		T_A = –10 °C–85 °C	V_{BAT} = 1.6 V–3.6 V	0	–	15	mA
			V_{BAT} = 0.8 V–1.6 V	0	–	25	mA
			V_{BAT} = 1.3 V–2.5 V	0	–	50	mA
			V_{BAT} = 2.5 V–3.6 V	0	–	50	mA
		T_A = –40 °C–85 °C	V_{BAT} = 1.8 V–2.5 V	0	–	50	mA
I_{LPK}	Inductor peak current			–	–	700	mA
I_Q	Quiescent current	Boost active mode		–	250	–	µA
		Boost sleep mode, I_{OUT} < 1 µA		–	25	–	µA
Reg_{LOAD}	Load regulation			–	–	10	%
Reg_{LINE}	Line regulation			–	–	10	%

Notes
29. Listed vsel options are characterized. Additional VSEL options are valid and guaranteed by design.
30. The boost will start at all valid V_{BAT} conditions including down to V_{BAT} = 0.5 V.
31. If V_{BAT} is greater than or equal to V_{OUT} boost setting, then V_{OUT} will be less than V_{BAT} due to resistive losses in the boost circuit.

Figure 11-15. GPIO Output High Voltage and Current

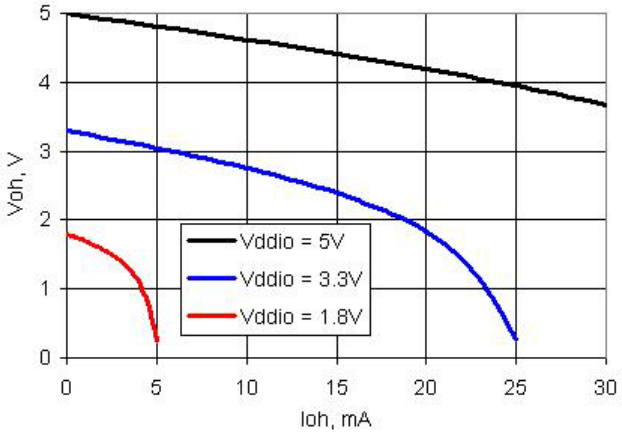


Figure 11-16. GPIO Output Low Voltage and Current

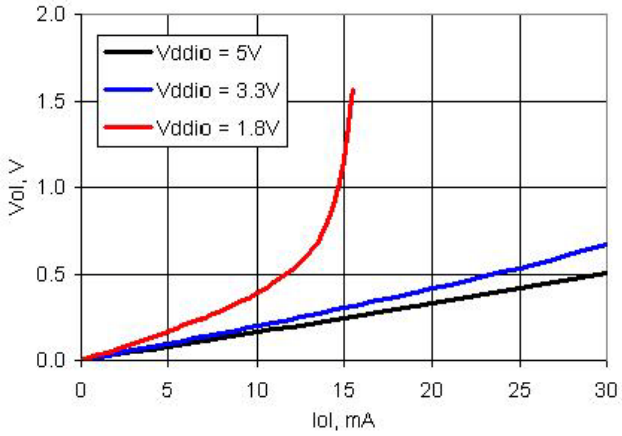


Table 11-9. GPIO AC Specifications[36]

Parameter	Description	Conditions	Min	Typ	Max	Units
TriseF	Rise time in Fast Strong Mode	3.3 V V_{DDIO} Cload = 25 pF	–	–	6	ns
TfallF	Fall time in Fast Strong Mode	3.3 V V_{DDIO} Cload = 25 pF	–	–	6	ns
TriseS	Rise time in Slow Strong Mode	3.3 V V_{DDIO} Cload = 25 pF	–	–	60	ns
TfallS	Fall time in Slow Strong Mode	3.3 V V_{DDIO} Cload = 25 pF	–	–	60	ns
Fgpioout	GPIO output operating frequency					
	2.7 V ≤ V_{DDIO} ≤ 5.5 V, fast strong drive mode	90/10% V_{DDIO} into 25 pF	–	–	33	MHz
	1.71 V ≤ V_{DDIO} < 2.7 V, fast strong drive mode	90/10% V_{DDIO} into 25 pF	–	–	20	MHz
	3.3 V ≤ V_{DDIO} ≤ 5.5 V, slow strong drive mode	90/10% V_{DDIO} into 25 pF	–	–	7	MHz
	1.71 V ≤ V_{DDIO} < 3.3 V, slow strong drive mode	90/10% V_{DDIO} into 25 pF	–	–	3.5	MHz
Fgpioin	GPIO input operating frequency	90/10% V_{DDIO}	–	–	33	MHz

Note
36. Based on device characterization (Not production tested).

Table 11-11 SIO AC Specifications[39]

Parameter	Description	Conditions	Min	Typ	Max	Units
TriseF	Rise time in fast strong mode (90/10%)	Cload = 25 pF, V_{DDIO} = 3.3 V	–	–	12	ns
TfallF	Fall time in fast strong mode (90/10%)	Cload = 25 pF, V_{DDIO} = 3.3 V	–	–	12	ns
TriseS	Rise time in slow strong mode (90/10%)	Cload = 25 pF, V_{DDIO} = 3.0 V	–	–	75	ns
TfallS	Fall time in slow strong mode (90/10%)	Cload = 25 pF, V_{DDIO} = 3.0 V	–	–	60	ns
Fsioout	SIO output operating frequency					
	2.7 V < V_{DDIO} < 5.5 V, Unregulated output (GPIO) mode, fast strong drive mode	90/10% V_{DDIO} into 25 pF	–	–	33	MHz
	1.71 V < V_{DDIO} < 2.7 V, Unregulated output (GPIO) mode, fast strong drive mode	90/10% V_{DDIO} into 25 pF	–	–	16	MHz
	3.3 V < V_{DDIO} < 5.5 V, Unregulated output (GPIO) mode, slow strong drive mode	90/10% V_{DDIO} into 25 pF	–	–	5	MHz
	1.71 V < V_{DDIO} < 3.3 V, Unregulated output (GPIO) mode, slow strong drive mode	90/10% V_{DDIO} into 25 pF	–	–	4	MHz
	2.7 V < V_{DDIO} < 5.5 V, Regulated output mode, fast strong drive mode	Output continuously switching into 25 pF	–	–	20	MHz
	1.71 V < V_{DDIO} < 2.7 V, Regulated output mode, fast strong drive mode	Output continuously switching into 25 pF	–	–	10	MHz
	1.71 V < V_{DDIO} < 5.5 V, Regulated output mode, slow strong drive mode	Output continuously switching into 25 pF	–	–	2.5	MHz
Fsioin	SIO input operating frequency					
	1.71 V ≤ V_{DDIO} ≤ 5.5 V	90/10% V_{DDIO}	–	–	33	MHz

Note
39. Based on device characterization (Not production tested).

11.5.5 Analog Globals

Table 11-30. Analog Globals DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
Rppag	Resistance pin-to-pin through P2[4], AGL0, DSM INP, AGL1, P2[5][55, 57]	V_{DDA} = 3.0 V	–	1500	2200	Ω
		V_{DDA} = 1.71 V	–	1200	1700	Ω
Rppmuxbus	Resistance pin-to-pin through P2[3], amuxbusL, P2[4][55, 57]	V_{DDA} = 3.0 V	–	700	1100	Ω
		V_{DDA} = 1.71 V	–	600	900	Ω

Table 11-31. Analog Globals AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
	Inter-pair crosstalk for analog routes[56]		106	–	–	dB
BWag	Analog globals 3 db bandwidth[56]	V_{DDA} = 3.0 V, 25 °C	–	26	–	MHz

Notes
55. Based on device characterization (Not production tested).
56. Pin P6[4] to del-sig ADC input; calculated, not measured.
57. The resistance of the analog global and analog mux bus is high if $V_{DDA} \leq 2.7$ V, and the chip is in either sleep or hibernate mode. Use of analog global and analog mux bus under these conditions is not recommended.

11.5.6 Comparator

Table 11-32. Comparator DC Specifications[58]

Parameter	Description	Conditions	Min	Typ	Max	Units
V_{OS}	Input offset voltage in fast mode	Factory trim, Vdda > 2.7 V, Vin ≥ 0.5 V	–		10	mV
	Input offset voltage in slow mode	Factory trim, Vin ≥ 0.5 V	–		9	mV
V_{OS}	Input offset voltage in fast mode[59]	Custom trim	–	–	4	mV
	Input offset voltage in slow mode[59]	Custom trim	–	–	4	mV
V_{OS}	Input offset voltage in ultra low power mode		–	±12	–	mV
TCVos	Temperature coefficient, input offset voltage	V_{CM} = V_{DDA} / 2, fast mode	–	63	85	µV/°C
		V_{CM} = V_{DDA} / 2, slow mode	–	15	20	
V_{HYST}	Hysteresis	Hysteresis enable mode	–	10	32	mV
V_{ICM}	Input common mode voltage	High current / fast mode	V_{SSA}	–	V_{DDA}	V
		Low current / slow mode	V_{SSA}	–	V_{DDA}	V
		Ultra low power mode	V_{SSA}	–	V_{DDA} – 1.15	V
CMRR	Common mode rejection ratio		–	50	–	dB
I_{CMP}	High current mode/fast mode		–	–	400	µA
	Low current mode/slow mode		–	–	100	µA
	Ultra low power mode		–	6	–	µA

Table 11-33. Comparator AC Specifications[58]

Parameter	Description	Conditions	Min	Typ	Max	Units
T_{RESP}	Response time, high current mode[59]	50 mV overdrive, measured pin-to-pin	–	75	110	ns
	Response time, low current mode[59]	50 mV overdrive, measured pin-to-pin	–	155	200	ns
	Response time, ultra low power mode[59]	50 mV overdrive, measured pin-to-pin	–	55	–	µs

Notes
58. The recommended procedure for using a custom trim value for the on-chip comparators can be found in the TRM.
59. Based on device characterization (Not production tested).

Figure 11-53. IDAC Full Scale Error vs Temperature, Range = 255 µA, Source Mode

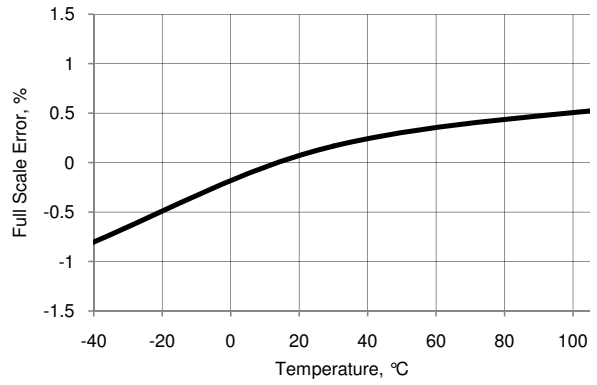


Figure 11-54. IDAC Full Scale Error vs Temperature, Range = 255 µA, Sink Mode

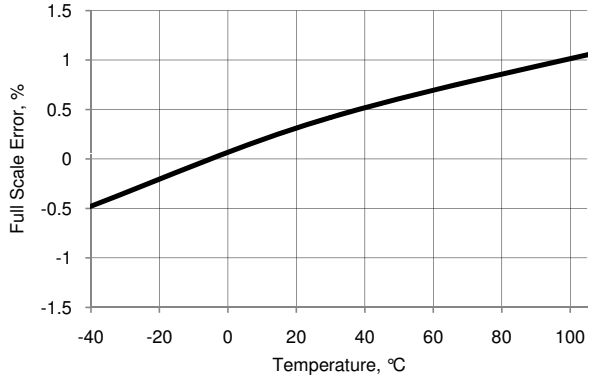


Figure 11-55. IDAC Operating Current vs Temperature, Range = 255 µA, Code = 0, Source Mode

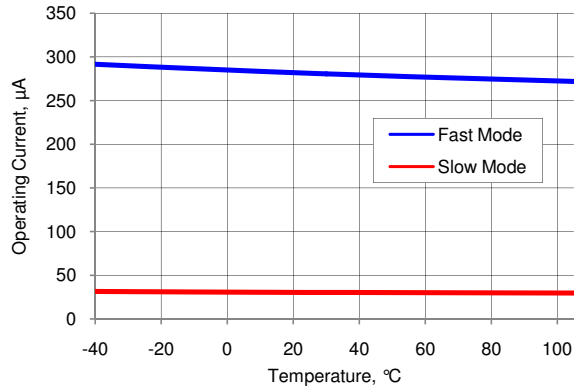
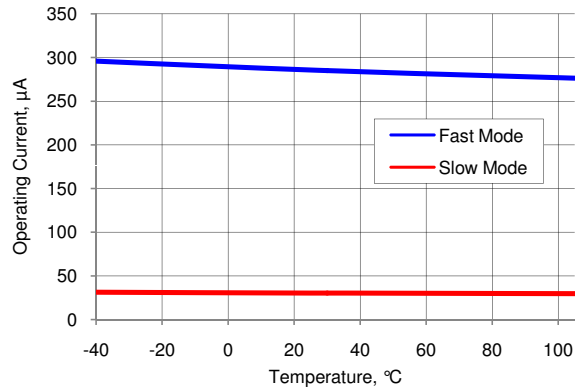


Figure 11-56. IDAC Operating Current vs Temperature, Range = 255 µA, Code = 0, Sink Mode



11.5.8 Voltage Digital to Analog Converter (VDAC)

See the VDAC component datasheet in PSoC Creator for full electrical specifications and APIs.

Unless otherwise specified, all charts and graphs show typical values.

Table 11-36. VDAC DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
	Resolution		–	8	–	bits
INL1	Integral nonlinearity	1 V scale	–	±2.1	±2.5	LSB
INL4	Integral nonlinearity[63]	4 V scale	–	±2.1	±2.5	LSB
DNL1	Differential nonlinearity	1 V scale	–	±0.3	±1	LSB
DNL4	Differential nonlinearity[63]	4 V scale	–	±0.3	±1	LSB
Rout	Output resistance	1 V scale	–	4	–	kΩ
		4 V scale	–	16	–	kΩ
V_{OUT}	Output voltage range, code = 255	1 V scale	–	1.02	–	V
		4 V scale, Vdda = 5 V	–	4.08	–	V
	Monotonicity		–	–	Yes	–
V_{OS}	Zero scale error		–	0	±0.9	LSB
Eg	Gain error	1 V scale	–	–	±2.5	%
		4 V scale	–	–	±2.5	%
TC_Eg	Temperature coefficient, gain error	1 V scale	–	–	0.03	%FSR / °C
		4 V scale	–	–	0.03	%FSR / °C
I_{DD}	Operating current[63]	Slow mode	–	–	100	µA
		Fast mode	–	–	500	µA

Figure 11-61. VDAC INL vs Input Code, 1 V Mode

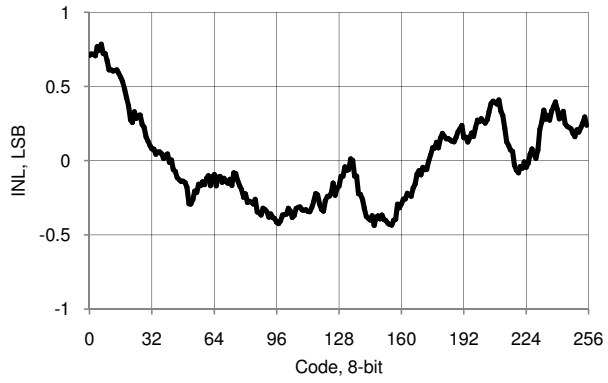
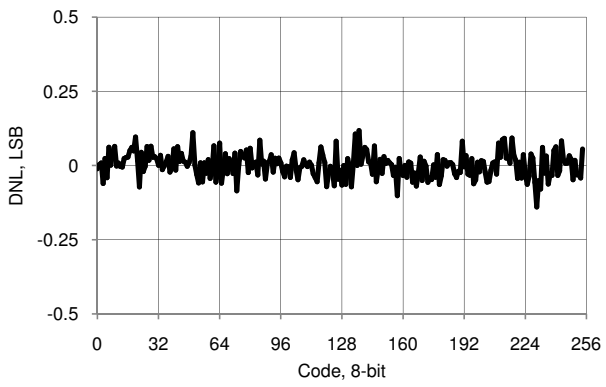


Figure 11-62. VDAC DNL vs Input Code, 1 V Mode



Note
63. Based on device characterization (Not production tested).

Figure 11-63. VDAC INL vs Temperature, 1 V Mode

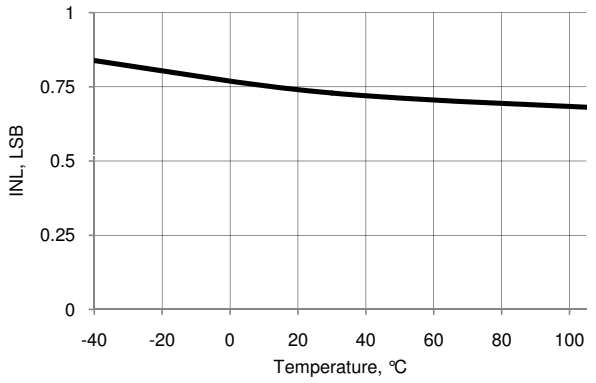


Figure 11-64. VDAC DNL vs Temperature, 1 V Mode

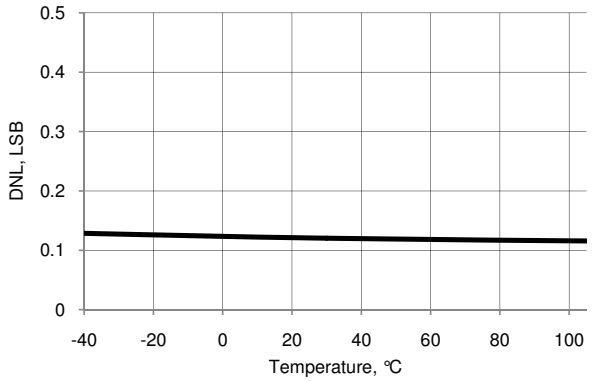


Figure 11-65. VDAC Full Scale Error vs Temperature, 1 V Mode

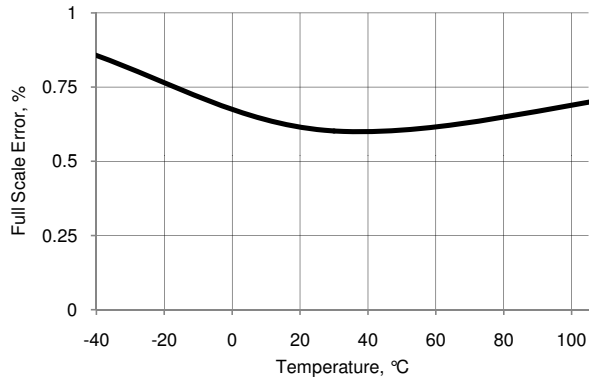


Figure 11-66. VDAC Full Scale Error vs Temperature, 4 V Mode

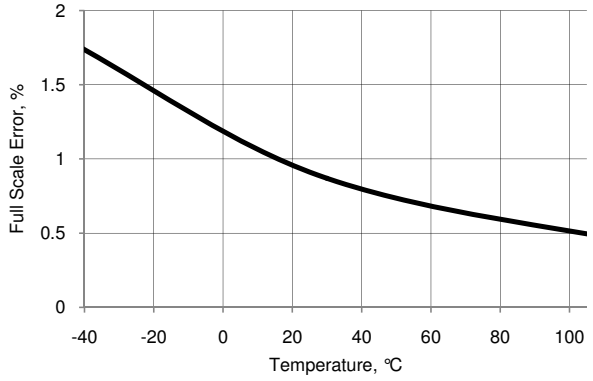


Figure 11-67. VDAC Operating Current vs Temperature, 1V Mode, Slow Mode

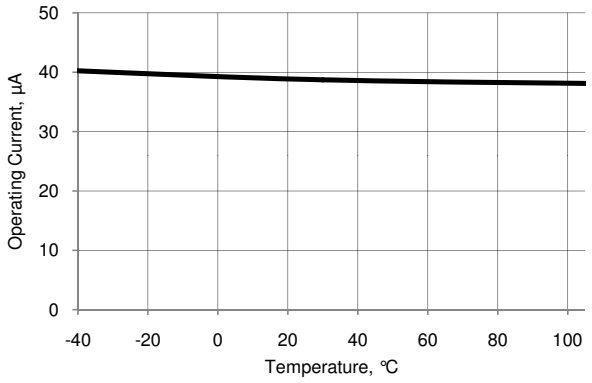


Figure 11-68. VDAC Operating Current vs Temperature, 1 V Mode, Fast Mode

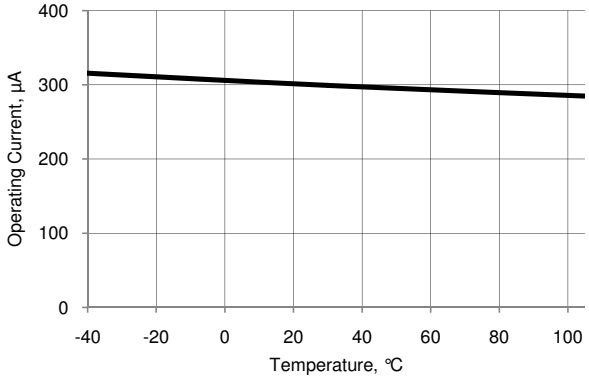


Table 11-80. IMO AC Specifications (continued)

Parameter	Description	Conditions	Min	Typ	Max	Units
Tstart_imo	Startup time[100]	From enable (during normal system operation)	–	–	13	µs
Jp-p	Jitter (peak to peak)[100]					
	F = 24 MHz		–	0.9	–	ns
	F = 3 MHz		–	1.6	–	ns
Jperiod	Jitter (long term)[101]					
	F = 24 MHz		–	0.9	–	ns
	F = 3 MHz		–	12	–	ns

Figure 11-82. IMO Frequency Variation vs. Temperature

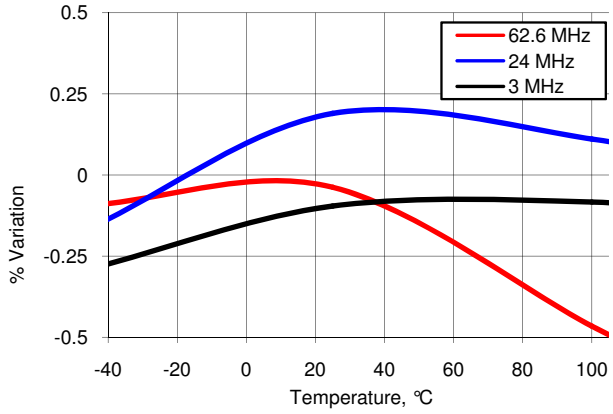
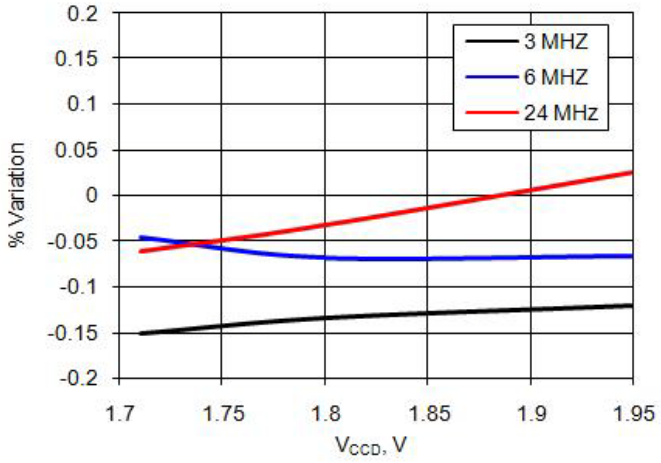


Figure 11-83. IMO Frequency Variation vs. V_{CC}



Notes
99. F_{IMO} is measured after packaging, and thus accounts for substrate and die attach stresses.
100. Based on device characterization (Not production tested).
101. Based on device characterization (Not production tested). USBIO pins tied to ground (VSSD).

11.9.3 MHz External Crystal Oscillator

For more information on crystal or ceramic resonator selection for the MHzECO, refer to application note AN54439: PSoC 3 and PSoC 5 External Oscillators.

Table 11-83. MHzECO DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
I_{CC}	Operating current[104]	13.56 MHz crystal	–	3.8	–	mA

Table 11-84. MHzECO AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
F	Crystal frequency range		4	–	25	MHz

11.9.4 kHz External Crystal Oscillator

Table 11-85. kHzECO DC Specifications[104]

Parameter	Description	Conditions	Min	Typ	Max	Units
I_{CC}	Operating current	Low power mode; CL = 6 pF	–	0.25	1.0	µA
DL	Drive level		–	–	1	µW

Table 11-86. kHzECO AC Specifications[104]

Parameter	Description	Conditions	Min	Typ	Max	Units
F	Frequency		–	32.768	–	kHz
T_{ON}	Startup time	High power mode	–	1	–	s

11.9.5 External Clock Reference

Table 11-87. External Clock Reference AC Specifications[104]

Parameter	Description	Conditions	Min	Typ	Max	Units
	External frequency range		0	–	33	MHz
	Input duty cycle range	Measured at $V_{DDIO}/2$	30	50	70	%
	Input edge rate	V_{IL} to V_{IH}	0.5	–	–	V/ns

11.9.6 Phase-Locked Loop

Table 11-88. PLL DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
I_{DD}	PLL operating current	In = 3 MHz, Out = 80 MHz	–	650	–	µA
		In = 3 MHz, Out = 67 MHz	–	400	–	µA
		In = 3 MHz, Out = 24 MHz	–	200	–	µA

Table 11-89. PLL AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
Fpllin	PLL input frequency[105]		1	–	48	MHz
	PLL intermediate frequency[106]	Output of prescaler	1	–	3	MHz
Fpllout	PLL output frequency[105]		24	–	80	MHz
	Lock time at startup		–	–	250	µs
Jperiod-rms	Jitter (rms)[104]		–	–	250	ps

Notes
104.Based on device characterization (Not production tested).
105.This specification is guaranteed by testing the PLL across the specified range using the IMO as the source for the PLL.
106.PLL input divider, Q, must be set so that the input frequency is divided down to the intermediate frequency range. Value for Q ranges from 1 to 16.

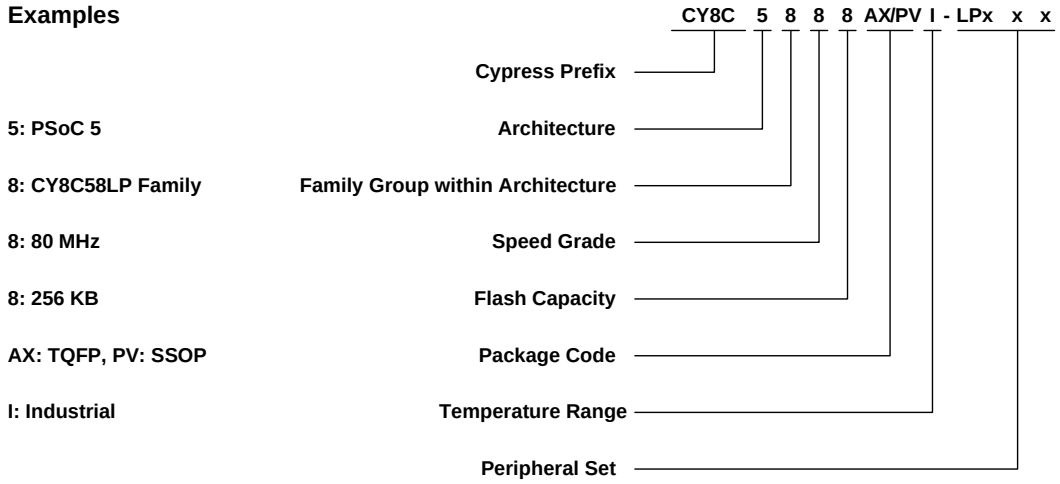
12.1 Part Numbering Conventions

PSoC 5LP devices follow the part numbering convention described here. All fields are single character alphanumeric (0, 1, 2, …, 9, A, B, …, Z) unless stated otherwise.

CY8Cabcdefg-LPxxx

- a: Architecture
  - 3: PSoC 3
  - 5: PSoC 5
- b: Family group within architecture
  - 2: CY8C52LP family
  - 4: CY8C54LP family
  - 6: CY8C56LP family
  - 8: CY8C58LP family
- c: Speed grade
  - 6: 67 MHz
  - 8: 80 MHz
- d: Flash capacity
  - 5: 32 KB
  - 6: 64 KB
  - 7: 128 KB
  - 8: 256 KB
- ef: Package code
  - Two character alphanumeric
  - AX: TQFP
  - LT: QFN
  - PV: SSOP
  - FN: CSP
- g: Temperature Range
  - C: Commercial
  - I: Industrial
  - Q: Extended
  - A: Automotive
- xxx: Peripheral set
  - Three character numeric
  - No meaning is associated with these three characters

Examples



Tape and reel versions of these devices are available and are marked with a “T” at the end of the part number.

All devices in the PSoC 5LP CY8C58LP family comply to RoHS-6 specifications, demonstrating the commitment by Cypress to lead-free products. Lead (Pb) is an alloying element in solders that has resulted in environmental concerns due to potential toxicity. Cypress uses nickel-palladium-gold (NiPdAu) technology for the majority of leadframe-based packages.

A high level review of the Cypress Pb-free position is available on our website. Specific package information is also available. Package Material Declaration Datasheets (PMDDs) identify all substances contained within Cypress packages. PMDDs also confirm the absence of many banned substances. The information in the PMDDs will help Cypress customers plan for recycling or other “end of life” requirements.

13. Packaging

Table 13-1. Package Characteristics

Parameter	Description	Conditions	Min	Typ	Max	Units
T_A	Operating ambient temperature		–40	25	105	°C
T_J	Operating junction temperature		–40	–	120	°C
T_{JA}	Package θ_{JA} (68-pin QFN)		–	15	–	°C/Watt
T_{JA}	Package θ_{JA} (100-pin TQFP)		–	34	–	°C/Watt
T_{JC}	Package θ_{JC} (68-pin QFN)		–	13	–	°C/Watt
T_{JC}	Package θ_{JC} (100-pin TQFP)		–	10	–	°C/Watt
T_A	Operating ambient temperature	For CSP parts	–40	25	85	°C
T_J	Operating junction temperature	For CSP parts	–40	–	100	°C
T_{JA}	Package θ_{JA} (99-ball CSP)			16.5		°C/Watt
T_{Jc}	Package θ_{JC} (99-ball CSP)		–	0.1	–	°C/Watt

Table 13-2. Solder Reflow Peak Temperature

Package	Maximum Peak Temperature	Maximum Time at Peak Temperature
68-pin QFN	260 °C	30 seconds
100-pin TQFP	260 °C	30 seconds
99-ball WLCSP	255 °C	30 seconds

Table 13-3. Package Moisture Sensitivity Level (MSL), IPC/JEDEC J-STD-2

Package	MSL
68-pin QFN	MSL 3
100-pin TQFP	MSL 3
99-ball WLCSP	MSL1